

EQUINOX 100: A remarkable desktop x-ray diffractometer designed to out perform all others



Complete diffraction pattern in seconds

Simultaneous, real time measurement of the entire 2 theta range at high resolution

Ultra high brilliance x-ray source with focusing optic technology

Plugs into standard 110V outlet

No external cooling water supply necessary

No moving parts!

Reflection or transmission mode

Phase identification and quantification, Rietveld analysis

Equinox 100: Designed for QA applications and routine x-ray diffraction studies. Suitable for research in fields such as chemical, environmental, metallurgical, geological, cement, mining and pharmaceuticals



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*Practical XRF & XRD
Training by the Industry's
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for
Diffraction Data*

*Live Instrumentation
Hands-on Training
Theoretical Lectures*

Rietveld Refinement & Indexing:

Basic Workshop 30 September–2 October 2013

Advanced Workshop 3–4 October 2013

Handheld XRF Workshop 15–17 October 2013

Practical X-ray Fluorescence Spectrometry
28 April–2 May 2014

Fundamentals of X-ray Powder Diffraction—XRD I
2–6 June 2014

Advanced Methods in X-ray Powder Diffraction—XRD II
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Your solution for powder analysis and more

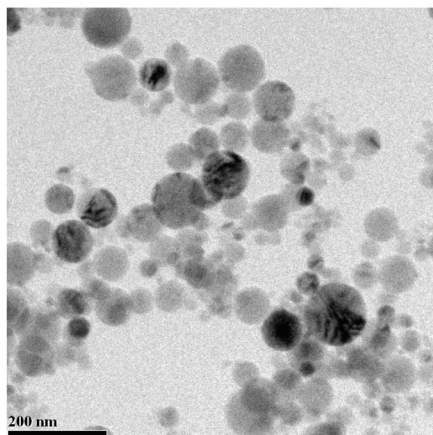


Versatile and easy to use

The basic configuration enables powder analysis by phase identification and quantification.

With easy and affordable extensions you can also:

- Analyze thin films
- Determine nanoparticle size distributions
- Investigate temperature-dependent material properties
- Perform automated analyses of multiple samples
- Benefit from the latest developments on optics, sample stages, detectors, X-ray tubes and analysis software



State-of-the-art performance for an attractive price

- High-speed, high-quality data acquisition
- Up to five times faster than a benchtop system
- Multiple options for additional applications
- Automatic sample changer available
- Comprehensive and easy-to-use software
- More than 10 years of proven quality
- Community of over 2500 user sites

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